

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Marco Wedowski et al. Art Unit : 2837  
Serial No. : 10/598,481 Examiner : Unknown  
Filed : August 31, 2006 Conf. No. : 5997  
Title : METHODS FOR MANUFACTURING REFLECTIVE OPTICAL ELEMENTS,  
REFLECTIVE OPTICAL ELEMENTS, EUV-LITHOGRAPHY APPARATUSES  
AND METHODS FOR OPERATING OPTICAL ELEMENTS AND EUV-  
LITHOGRAPHY APPARATUSES, METHODS FOR DETERMINING THE  
PHASE SHIFT, METHODS FOR...

**MAIL STOP AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

Applicants also enclose a copy of the International Search Report for the corresponding PCT Application No. PCT/EP2005/050985.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: June 29, 2007

/Sean P. Daley/

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Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 17979-046US1	Application No. 10/598,481
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Marco Wedowski et al.		
		Filing Date August 31, 2006	Group Art Unit	

<b>U.S. Patent Documents</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,307,395	4/26/1994	Seely et al.			
	AB	6,781,685	8/24/2004	Hamm			
	AC	2005/0104015	5/19/2005	Wedowski et al.			
	AD	2005/0087699	4/28/2005	Miyake			
	AE	2007/0114466	5/24/2007	Wedowski et al.			

<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AF	1 243 970	9/25/2002	EP			
	AG	1 351 258	10/8/2003	EP			X
	AH	1 351 258	10/8/2003	EP			Abstract only
	AI	2002-243669	8/28/2002	JP			X
	AJ	2002-243669	8/28/2002	JP			Abstract only
	AK	WO 04/10755	1/29/2004	WIPO			

<b>Other Documents (include Author, Title, Date, and Place of Publication)</b>		
Examiner Initial	Desig. ID	Document
	AL	Y. Muramatsu et al., "Total-electron-yield X-ray standing-wave measurements of multilayer X-ray mirrors for the interface structure evaluation," Microprocesses and Nanotechnology Conference, October 2001 International, 2001.

Examiner Signature /Steven Whitesell Gordon/ (08/13/2010)	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	